

### **Abstract of the Disclosure**

Apparatus for measuring sidewall thickness of a container includes a conveyor for moving the container transversely of its axis through an inspection station and simultaneously rotating the container about its axis. A light source and an illumination lens system direct onto the sidewall of the container a line-shaped light beam having a long dimension perpendicular to the axis of the container and parallel to the direction of movement of the container through the inspection station. A light sensor and an imaging lens system direct onto the sensor light energy reflected from portions of the outer and inner sidewall surfaces that are perpendicular to the illumination light energy. An information processor is responsive to light energy directed onto the light sensor by the imaging lens system for determining the thickness of the container between the outer and inner sidewall surfaces.